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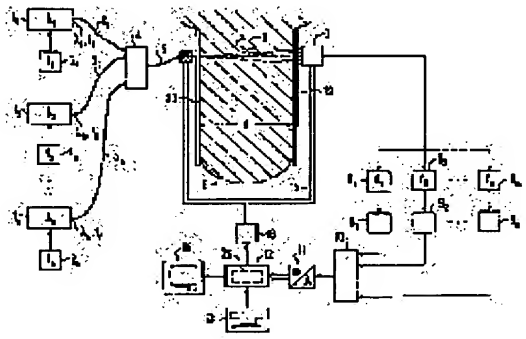
(54) TISSUE INSPECTION DEVICE BY LIGHT OF DIFFERENT WAVELENGTH

(57)Abstract:
PURPOSE: To provide knowledge about tissue components existing with relation to each inspection zone by a method of feeding signals equivalent to strengths of respective wavelength components detected by light detection means, and detecting data about thickness of the different tissue components from signals based on data memorized by an evaluation means.
CONSTITUTION: Measurement light signals are obtained by combining light supplied form light sources I1-In with each other using a light waveguide fine coupler 4. A detection means in the mode of a photomultiplier 7 is disposed on the opposite side of a sample 6 to face a light outgoing zone. Electric signals of the photomultiplier 7 are supplied to band path filters 81-8n, so a detection means is formed of both. These electric signals reach signal processing circuits 91-9n, and signal processing is performed to match respective inspection examples. Outputted signals reach an evaluation means in the mode of an electron computation device 12, and data of thickness of tissue components of a subject tissue is detected by use of data memorized in a memory 26.



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